



Mostafa Emam

CEO

INCIZE

<http://www.incize.com>

BILATERAL MEETINGS

02.03.2015 Monday (15.10h - 18.05h)

03.03.2015 Tuesday (9.00h - 11.05h)

03.03.2015 Tuesday (11.05h - 13.10h)

03.03.2015 Tuesday (13.10h - 15.15h)

03.03.2015 Tuesday (15.15h - 16.55h)

04.03.2015 Wednesday (9.00h - 11.05h)

04.03.2015 Wednesday (11.05h - 13.10h)

04.03.2015 Wednesday (13.10h - 15.15h)

04.03.2015 Wednesday (15.15h - 16.55h)

DESCRIPTION Incize is your partner in semiconductor characterization and modeling for the design of digital, analog/RF and harsh environment applications. Incize is the fruit of many years of experience in the field of semiconductors characterization and design of digital, analog/RF and harsh environment applications. Incize is a spin-off from the Université catholique de Louvain (UCL) in Belgium; one of the most prestigious universities in Europe and the house of worldwide known laboratories and research centers.

ORGANIZATION TYPE Company

ORGANIZATION SIZE 1-10

FOUNDING YEAR 2014

LINKEDIN <http://be.linkedin.com/pub/mostafa-emam>

AREAS OF ACTIVITIES

HARDWARE

1. Semiconductors
2. Test and measurement equipment

SERVICES/OTHERS

1. Outsourcing

Offer

SEMICONDUCTOR CHARACTERISATION AND MODELLING

We provide:□

- DC to 110 GHz on-wafer and packaged device measurements□
- Harmonic distortion measurements with an input power ranging from -25 dBm to +40 dBm with 165 dBc.
- Radiation hardness characterization and modeling services.
- Load-pull measurements.
- Extreme temperature environments (4 K to 600 K). □
- TCAD simulations of novel structures and materials
- Thermal (RF) noise measurement and modeling for Si and III-V devices in a frequency range from 1 GHz to 60 GHz.

Further information:

http://incize.com/wp-content/uploads/2014/10/Incize_FactSheet_2014.pdf

KEYWORDS: SEMICONDUCTORS RF SOI RADIATION HARDNESS LOW POWER HIGH POWER MEASUREMENT CHARACTERISATION MODELLING WIDE BAND NOISE

COOPERATION OFFERED

1. Technical co-operation

COOPERATION REQUESTED

1. Outsourcing co-operation
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